Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/644,966	NAKAZAWA ET AL.	
Examiner	Art Unit	
Lois Zheng	1742	

SEARCHED					
Class	Subclass	Date	Examiner		
204	232	3/23/2006	LLZ		
204	237-238	3/23/2006	LLZ		
204	240, 242	3/23/2006	LLZ		
204	252	3/23/2006	LLZ		
204	275.1	3/23/2006	LLZ		
205	334	3/23/2006	LLZ		
205	633,637	3/23/2006	LLZ		

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
			-		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Inventorship Search	3/23/2006	LLZ		
Updated EAST Search	3/24/2006	LLZ		
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